# **BSN20**

N-channel enhancement mode field-effect transistor

Rev. 03 — 26 June 2000

**Product specification** 

## 1. Description

N-channel enhancement mode field-effect transistor in a plastic package using TrenchMOS<sup>TM1</sup> technology.

Product availability:

BSN20 in SOT23.

### 2. Features

- TrenchMOS<sup>™</sup> technology
- Very fast switching
- Logic level compatible
- Subminiature surface mount package.

## 3. Applications

- Relay driver
- High speed line driver
- Logic level translator.

## 4. Pinning information

Table 1: Pinning - SOT23, simplified outline and symbol

Pin	Description	Simplified outline	Symbol	
1	gate (g)	3		
2	source (s)		d	
3	drain (d)	03ab44	g	
		SOT23	N-channel MOSFET	

<sup>1.</sup> TrenchMOS is a trademark of Royal Philips Electronics.





#### N-channel enhancement mode field-effect transistor

## 5. Quick reference data

Table 2: Quick reference data

Symbol	Parameter	Conditions	Тур	Max	Unit
$V_{DS}$	drain-source voltage (DC)	T <sub>j</sub> = 25 to 150 °C	_	50	V
$I_D$	drain current (DC)	$T_{sp} = 25 ^{\circ}C; V_{GS} = 10 ^{\circ}V$	-	173	mA
P <sub>tot</sub>	total power dissipation	$T_{sp} = 25  ^{\circ}C$	-	0.83	W
Tj	junction temperature		_	150	°C
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 100 \text{ mA}$	2.8	15	Ω
		$V_{GS} = 5 \text{ V}; I_D = 100 \text{ mA}$	3.8	20	Ω

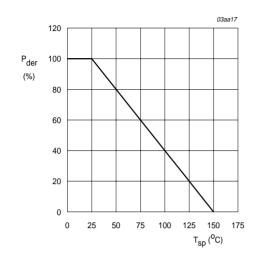
## 6. Limiting values

Table 3: Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

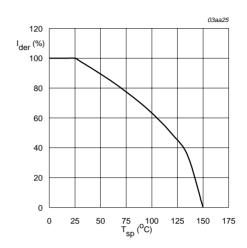
Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage (DC)	T <sub>j</sub> = 25 to 150 °C	_	50	V
$V_{DGR}$	drain-gate voltage (DC)	$T_j$ = 25 to 150 °C; $R_{GS}$ = 20 $k\Omega$	_	50	V
$V_{GS}$	gate-source voltage (DC)		_	±20	V
I <sub>D</sub>	drain current (DC)	$T_{sp}$ = 25 °C; $V_{GS}$ = 10 V; Figure 2 and 3	_	173	mA
		T <sub>sp</sub> = 100 °C; V <sub>GS</sub> = 10 V; Figure 2	_	110	mA
I <sub>DM</sub>	peak drain current	$T_{sp}$ = 25 °C; pulsed; $t_p \le 10 \mu s$ ; Figure 3	_	0.7	А
P <sub>tot</sub>	total power dissipation	T <sub>sp</sub> = 25 °C; Figure 1	_	0.83	W
T <sub>stg</sub>	storage temperature		-65	+150	°C
Tj	operating junction temperature		-65	+150	°C
Source-drain diode					
I <sub>S</sub>	source (diode forward) current (DC)	T <sub>sp</sub> = 25 °C	_	173	mA
I <sub>SM</sub>	peak source (diode forward) current	$T_{sp}$ = 25 °C; pulsed; $t_p \le 10 \mu s$	_	0.7	А

#### N-channel enhancement mode field-effect transistor



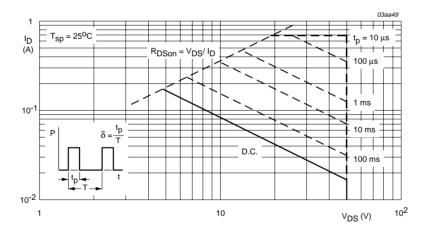
$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 1. Normalized total power dissipation as a function of solder point temperature.



$$V_{\text{GS}} \ge 5 \text{ V}$$
 
$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized continuous drain current as a function of solder point temperature.



 $T_{sp} = 25 \,^{\circ}\text{C}$ ;  $I_{DM}$  is single pulse.

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage.

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### 7. Thermal characteristics

Table 4: Thermal characteristics

Symbol	Parameter	Conditions	Value	Unit
R <sub>th(j-sp)</sub>	thermal resistance from junction to solder point	mounted on a metal clad substrate; Figure 4	150	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	mounted on a printed circuit board; minimum footprint	350	K/W

### 7.1 Transient thermal impedance

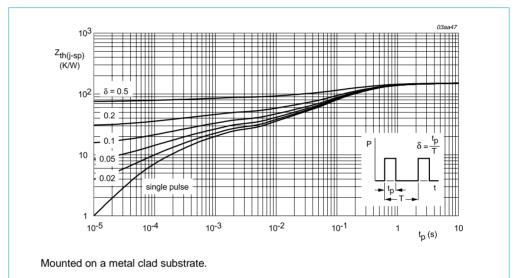


Fig 4. Transient thermal impedance from junction to solder point as a function of pulse duration.

#### N-channel enhancement mode field-effect transistor

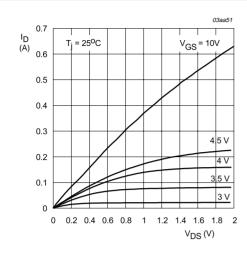
## 8. Characteristics

**Table 5: Characteristics** 

 $T_i = 25 \,^{\circ}C$  unless otherwise specified

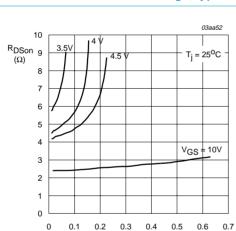
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V <sub>(BR)DSS</sub>	drain-source breakdown	$I_D = 10 \mu A; V_{GS} = 0 V$				
	voltage	T <sub>j</sub> = 25 °C	50	75	-	V
		T <sub>j</sub> = −55 °C	46	-	_	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; Figure 9				
		T <sub>j</sub> = 25 °C	0.4	1	_	V
		T <sub>j</sub> = 150 °C	0.3	-	-	V
		T <sub>j</sub> = −55 °C	_	_	3.5	V
DSS	drain-source leakage current	V <sub>DS</sub> = 40 V; V <sub>GS</sub> = 0 V				
		T <sub>j</sub> = 25 °C	_	0.01	1.0	μΑ
		T <sub>i</sub> = 150 °C	_	_	10	μΑ
l <sub>GSS</sub>	gate-source leakage current	$V_{GS} = \pm 20 \text{ V}; V_{DS} = 0 \text{ V}$	_	10	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 100 \text{ mA};$ Figure 7 and 8				
		T <sub>i</sub> = 25 °C	_	2.8	15	Ω
		T <sub>i</sub> = 150 °C	_	_	28	Ω
		$V_{GS} = 5 \text{ V}; I_D = 100 \text{ mA};$ Figure 7 and 8				
		T <sub>j</sub> = 25 °C	_	3.8	20	Ω
Dynamic (	characteristics					
g <sub>fs</sub>	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 100 \text{ mA};$ Figure 11	40	170	_	mS
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 10 \text{ V};$	_	17	25	pF
Coss	output capacitance	f = 1 MHz; Figure 12	_	7	15	pF
C <sub>rss</sub>	reverse transfer capacitance	-	_	4	8	pF
t <sub>on</sub>	turn-on time	$V_{DD} = 20 \text{ V}; R_D = 180 \Omega;$	_	1.7	8	ns
t <sub>off</sub>	turn-off time	$V_{GS}$ = 10 V; $R_G$ = 50 $\Omega$ ; $R_{GS}$ = 50 $\Omega$	-	8	15	ns
Source-dr	rain diode					
$V_{SD}$	source-drain (diode forward) voltage	$I_S = 180 \text{ mA}; V_{GS} = 0 \text{ V};$ Figure 13	_	0.9	1.5	V
·rr	reverse recovery time	I <sub>S</sub> = 180 mA;	_	30	_	ns
Q <sub>r</sub>	recovered charge	$dI_S/dt = -100 \text{ A/}\mu\text{s};$ $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}$	_	30	_	nC

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T<sub>j</sub> = 25 °C

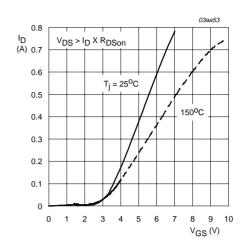
Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values.



T<sub>i</sub> = 25 °C

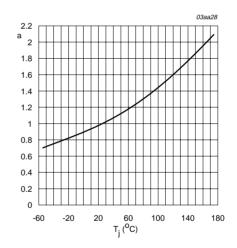
Fig 7. Drain-source on-state resistance as a function of drain current; typical values.

 $I_D(A)$ 



 $T_j = 25$  °C and 150 °C;  $V_{DS} \ge I_D \times R_{DSon}$ 

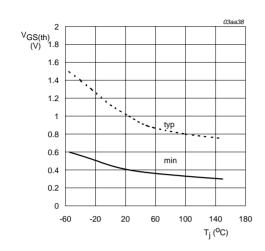
Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values.



 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$ 

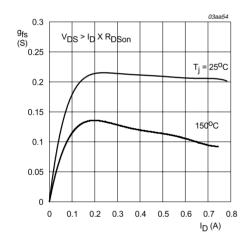
Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature.

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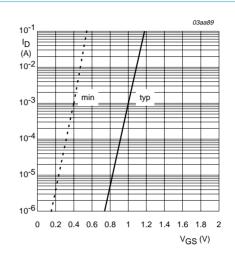
 $I_D = 1 \text{ mA}; V_{DS} = V_{GS}$ 

Fig 9. Gate-source threshold voltage as a function of junction temperature.



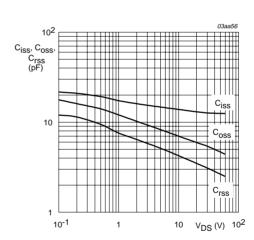
 $T_j$  = 25 °C and 150 °C;  $V_{DS} \ge I_D \times R_{DSon}$ 

Fig 11. Forward transconductance as a function of drain current; typical values.



 $T_i = 25 \,^{\circ}C; V_{DS} = 5 \,^{\circ}V$ 

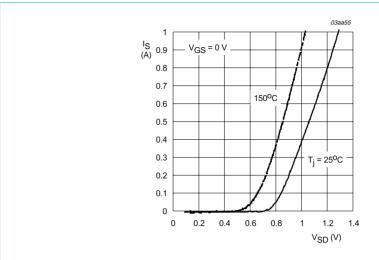
Fig 10. Sub-threshold drain current as a function of gate-source voltage.



 $V_{GS} = 0 V$ ; f = 1 MHz

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.

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 $T_j$  = 25 °C and 150 °C;  $V_{GS}$  = 0 V

Fig 13. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.

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## 9. Package outline

#### Plastic surface mounted package; 3 leads

SOT23

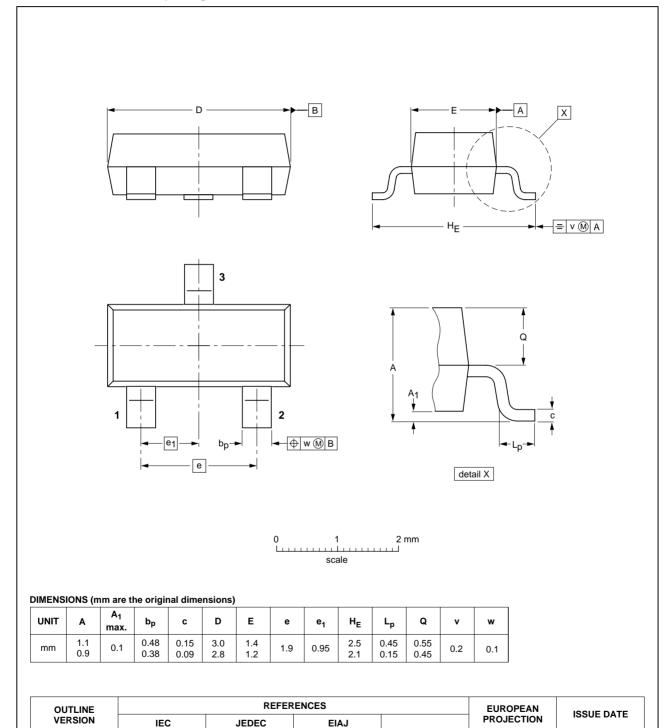


Fig 14. SOT23.

SOT23

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#### N-channel enhancement mode field-effect transistor

## 10. Revision history

#### Table 6: Revision history

Rev	Date	CPCN	Description
03	20000626	HZG303	Product specification; third version; supersedes BSN20_2 of 970618.
			Converted from VDMOS (Nijmegen) to TrenchMOS™ technology (Hazel Grove).
02	19970618	-	Product specification; second version.
01	19901031	-	Product specification; initial version.

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#### 11. Data sheet status

Datasheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

[1] Please consult the most recently issued data sheet before initiating or completing a design.

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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